

IEC and Academia



Jack Sheldon
IEC Standardization
Strategy Manager



IEC Masterplan 2006

- ...extend co-operation with and communication efforts in academic circles ... to develop and provide educational materials ...
- ... ensure that member National Committees
 (NCs) represent all relevant national interests
 ... include ... researchers, academics ...

10/08/2009 IEC and Academia

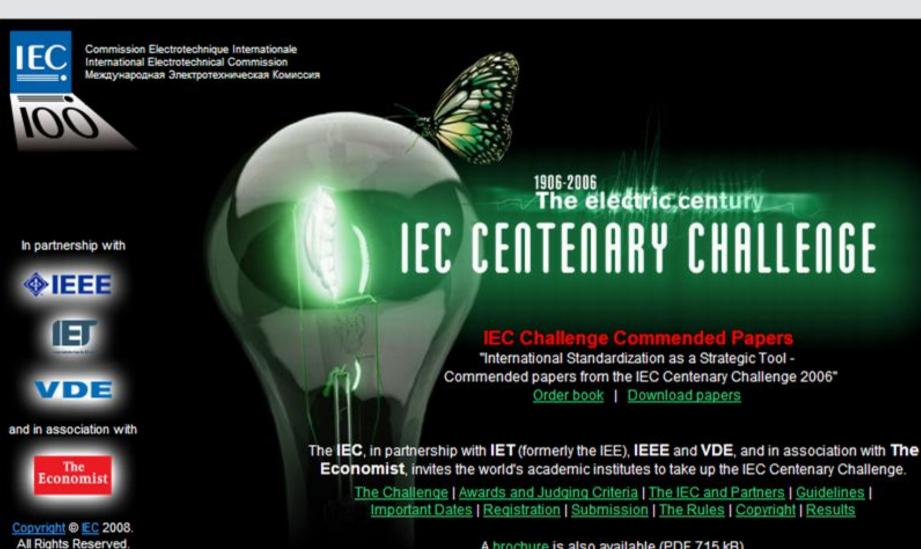


IEC Centenary Challenge (2006)

- 1906 2006 IEC Centenary
- Competition for papers for world's academic institutions "standards and business"
- For world's academic institutions
- In partnership with IEE (IET), IEEE, VDE and in association with The Economist
- Prizes (15 000\$, 5 000\$ and 2 000\$)



IEC Centenary Challenge



A brochure is also available (PDF 715 kB).



IEC Centenary Challenge

- ERC (Executive Review Council) eminent leaders from government, business, media
 - Dr. Arden Bement Jr., Director US National Science Foundation
 - Dr. Takuo Sugano, Tokyo University
 - Prof. Klaus Wucherer, Management Board, Siemens AG
 - Tom Standage, Technology Editor, The Economist
- Participation 100 institutions from 35 countries
- Award Ceremony at IET, London, December 2006



IEC Challenge Winners

1st prize

Université Toulouse III - Paul Sabatier, France

"Standardising Mesopic Vision Conditions and Incidence on Light

Sources Science and Technology"

Authors: Dr. Georges Zissis and Dr. Stuart Mucklejohn

2nd prize co-winners

University of Colorado at Boulder, USA

"The Entrepreneur and Standards"

Authors: Ken Krechmer and Elaine Baskin

University of Tokyo, Japan

"Architecture-based Approaches to International Standardization and

Evolution of Business Models"

Authors: Junjiro Shintaku, Koichi Ogawa and Tetsuo Yoshimoto

3rd prize

Toyo University, Japan

"Standardization and Patent Pools: Using Patent Licensing to Lead the

Market"

Authors: Hajime Yamada



IEC Centenary Challenge

- Publication of winning papers on IEC web site: http://www.iecchallenge.org
- IEC Challenge Book
 International Standardization as a Strategic
 Tool –
 Commended Papers from the IEC Centenary
 Challenge 2006



Academic papers

The articles listed below are the commended papers from the IEC Centenary Challenge. The IEC Centenary Challenge was a competition for papers on the economic, business and social impact of International Standards on business. It was organized in association with The Economist magazine and in partnership with three leading professional engineering bodies: the IET (Institute of Engineering and Technology); IEEE (Institute of Electrical and Electronics Engineers); and VDE, the German association for electrical, electronic and information technologies. The IEC Challenge Award Ceremony was held at Savoy Place, London, on 14 December 2006.

All articles are published in the book "International Standardization as a Strategic Tool", which can be purchased from the IEC Webstore

Commended papers (in alphabetical order)

Size

PDF 1'636 KB

Architecture-based approaches to international standardization and evolution of business models
Junjiro Shintaku (lead author); Koichi Ogawa, Tetsuo Yoshimoto (co-authors)
The University of Tokyo - Manufacturing Management Research Center, Japan

 Benefits of standardization in the microelectronics industries and their implications on nanotechnology and other innovative industries PDF 1'125 KB

Werner Bergholz (lead author); Bettina Weiss, Carlos Lee (co-authors) International University Bremen, Germany

Do national standards hinder or promote trade in electrical products?
 Johannes Moenius
 University of Redlands, USA

PDF 982 KB

Industrial legislatures: The American system of standardization

PDF 938 KB

Andrew Russell 10/08/2009



■ IEC Lectures Series I (2005) – Engineering

Developed by Don Purcell, Chairman and CEO of the Center for Global Standards Analysis at the Catholic University of America

■ IEC Lectures Series II (2007) – Business

Developed by Tineke M. Egyedi, Senior
Researcher Standardization, Delft University
of Technology, Netherlands



IEC Lecture series I (2005)

This first series of two lectures were developed for the IEC by Donald E. Purcell, Chairman and CEO of the Center for Global Standards Analysis at the Catholic University of America.

They are aimed at providing material for lectures in universities, business and engineering schools to support curricula covering standardization and its impact on business, industry and engineering. The two lectures will help in giving a general overview of international standardization and a basic knowledge about the IEC's activities. The IEC believes that students should understand the importance of international standardization in the context of the global market.

A CD-ROM comprising the two lectures and a copy of an IEC standard, IEC 61400-11, used in the presentations as an example of an IEC standard, is available from IEC Central Office.

International Standardization in Business, Industry, Society and Technology

- Lecture 1: The Strategic Value of International Standards
- Lecture 2: The International Electrotechnical Commission

IEC Lecture series II (2007)

This series of three lectures were developed for the IEC by Tineke M. Egyedi, Senior Researcher Standardization, Delft University of Technology, Netherlands.

The IEC Lecture Series II has been developed on the occasion of the IEC centenary as material for lectures specifically for business and management schools. The objective of these lectures is to create a better awareness and understanding of the importance of standards, their impact on business and industry, for students in business, management of technology, and for technology policy faculties of technica universities.

This series complements the first series of lectures.

The Importance of Standards

- Lecture 1: Introduction to Standards
- Lecture 2: Life Cycle of Standards
- Lecture 3: The Economic Value of Standards



About Standardization

- Three commented slide shows
 - Standardization Strategies Introduction to Standardization and to the IEC
 - IEC Structure and Membership
 - Development of Standards



About standardization

About standardization

Introduction

The series of three narrated slide shows listed below will give you an introduction to the IEC and standardization in general. They are complementary to the lecture series featured in this Academia section.

- Slide show 1
 Standardization strategies Introduction to standardization and to the IEC
- Slide show 2 IEC structure and membership
- Slide show 3 Development of standards

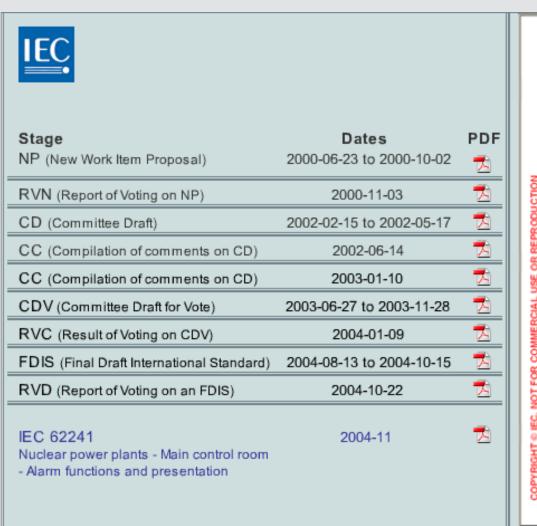




Sample standard and working documents development

- Samples of working documents illustrating the progression from initial proposal to final standard
- In the form of an animated presentation













IEC and Academia



IEC and Academia

This section of the IEC website is dedicated to the academic world, professors, researchers and students.

From academic papers on "Consideration of the economic, business and social impact of the development and use of International Standards for end-users at any level of business activity" to lecture series and basics on eletrotechnical standardization, we are making available a wealth of documents.

Academic papers

A library of recently published papers from Academia highlighting the social and economic benefits of International Standardization.

Lecture series

A resource developed specifically for use by lecturers in universities and business and engineering schools. All lectures in Powerpoint available for download (no request needed).

About standardization

These presentations take you through the standardization process - from an idea to a draft document to the consensus-based International Standard.

Sample standard & working documents development

Samples of working documents illustrating the progression from initial proposal to final standard.

Subscribe to e-mail alert services

To keep in touch with developments, we highlight the electronic newsletters available for free subscription.

IEC Challenge

The IEC competition organized in association with The Economist and in partnership with IET, IEEE and VDE.



Thank you

